Search Notes

Application/Control No.	. Applicant(s)/Patent under Reexamination	
10/660,460	OLDHAM ET AL.	
Examiner	Art Unit	
Patrick J. Lee	2878	

	SEAD	CHED	
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Class	Subclass	Date	Examiner
250	208.1, 234-236, 573	11/38/05	PL
382	145, 149		PL
356	237.4		PL
356	237.5	1	PL
Updated	search	36106	PL

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
Interfere Searl	atheld	3/7/2006		

SEARCH NOT (INCLUDING SEARCH S		<b>)</b>
	DATE	EXMR
Consulted w/ S. Allen AU 2878 CL 250	11/28/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	11/28/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	11/30/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	3/6/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	3/7/2006	PL